

AON2406

20V N-Channel MOSFET

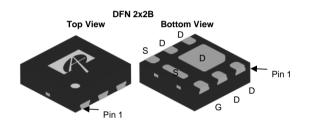
General Description

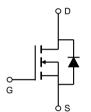
The AON2406 combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

Product Summary

 $\begin{array}{lll} V_{DS} & 20V \\ I_{D} \; (at \, V_{GS} \!\!=\!\! 4.5V) & 8A \\ R_{DS(ON)} \; (at \, V_{GS} \!\!=\!\! 4.5V) & < 12.5 m \Omega \\ R_{DS(ON)} \; (at \, V_{GS} \!\!=\!\! 2.5V) & < 15 m \Omega \\ R_{DS(ON)} \; (at \, V_{GS} \!\!=\!\! 1.8V) & < 19 m \Omega \\ R_{DS(ON)} \; (at \, V_{GS} \!\!=\!\! 1.5V) & < 24 m \Omega \end{array}$







Absolute Maximum Ratings T _A =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		V_{DS}	20	V				
Gate-Source Voltage		V_{GS}	±8	V				
Continuous Drain	T _A =25°C		8	۸				
Current ^G	T _A =70°C	'D	6	А				
Pulsed Drain Current C		I _{DM}	32					
	T _A =25°C	$-P_{D}$	2.8	W				
Power Dissipation A	T _A =70°C	- P	1.8	VV				
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C				

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	37	45	°C/W			
Maximum Junction-to-Ambient AD Steady-State		$R_{ heta JA}$	66	80	°C/W			



Electrical Characteristics (T₁=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
STATIC F	PARAMETERS			-		-
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V	20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V			1	
		T _J =55°C			5	μΑ
I _{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±8V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	0.4	0.67	1.0	V
I _{D(ON)}	On state drain current	V_{GS} =4.5V, V_{DS} =5V	32			Α
		V_{GS} =4.5V, I_D =8A		10	12.5	mO
		T _J =125°C		13.5	17	mΩ
R _{DS(ON)} Static	Static Drain-Source On-Resistance	V_{GS} =2.5V, I_D =6A		11.5	15	mΩ
		V_{GS} =1.8V, I_D =4A		14	19	mΩ
		V_{GS} =1.5V, I_D =1A		17	24	mΩ
g _{FS}	Forward Transconductance	V_{DS} =5V, I_{D} =8A		50		S
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V		0.6	1	V
Is	Maximum Body-Diode Continuous Curr	rent			4.5	Α
DYNAMIC	PARAMETERS		•		•	
C _{iss}	Input Capacitance			1140		pF
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =10V, f=1MHz		165		pF
C _{rss}	Reverse Transfer Capacitance	1		110		pF
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		2.2		Ω
SWITCHI	NG PARAMETERS		•		•	
Q_g	Total Gate Charge			12.5	18	nC
Q_{gs}	Gate Source Charge	V_{GS} =4.5V, V_{DS} =10V, I_{D} =8A		1.2		nC
Q_{gd}	Gate Drain Charge	1		2.7		nC
t _{D(on)}	Turn-On DelayTime			2.7		ns
t _r	Turn-On Rise Time	V_{GS} =4.5V, V_{DS} =10V, R_L =1.25 Ω ,		3		ns
t _{D(off)}	Turn-Off DelayTime	$R_{GEN}=3\Omega$		37		ns
t _f	Turn-Off Fall Time	7		7		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =8A, dI/dt=100A/μs		11		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =8A, dI/dt=100A/μs		3		nC
A Th	of R is measured with the device mounted on 1					

A. The value of R_{BJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R_{0JA} $t \le 10s$ value and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T_I(MAX)=150° C. Ratings are based on low frequency and duty cycles to keep initial

D. The R_{NJC} is the sum of the thermal impedance from junction to case R_{NJC} and case to ambient. E. The static characteristics in Figures 1 to 6 are obtained using <300 μ s pulses, duty cycle 0.5% max.

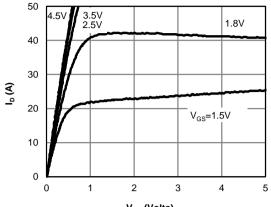
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{.I/MAX}=150° C. The SOA curve provides a single pulse rating.

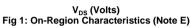
G. The maximum current rating is package limited.

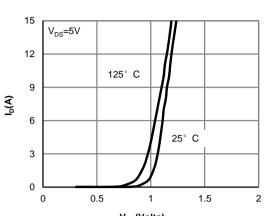
H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}$ C.



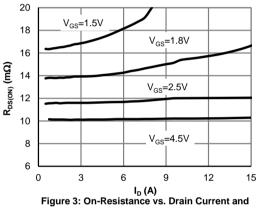
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



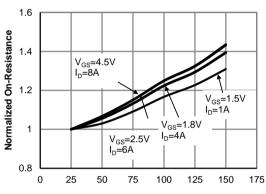




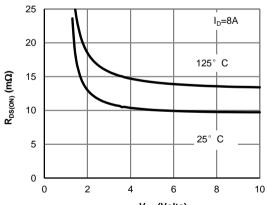
V_{GS}(Volts)
Figure 2: Transfer Characteristics (Note E)



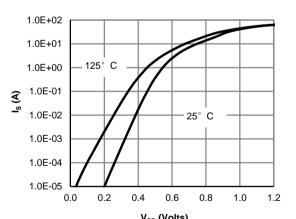
Gate Voltage (Note E)



Temperature (°C) Figure 4: On-Resistance vs. Junction Temperature (Note E)



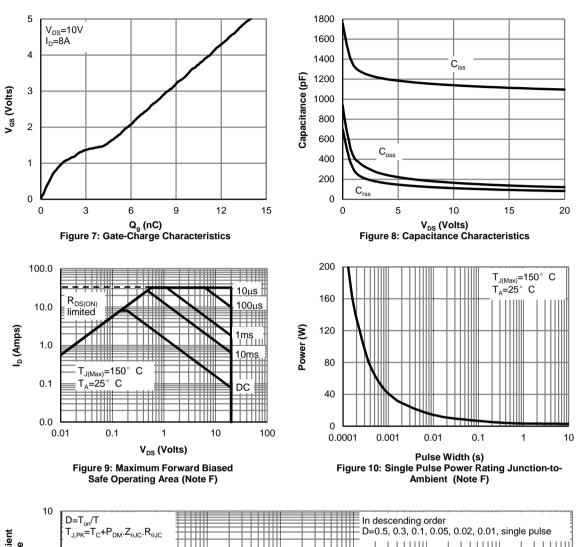
V_{GS} (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

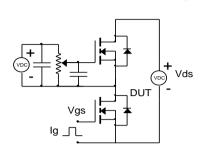


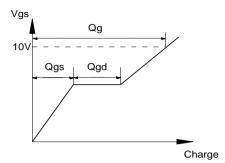
10 D=T_{or}/T T_{J,PK}=T_C+P_{DM}.Z_{0,JC}.R_{0,JC} D=0.5, 0.3, 0.1, 0.05, 0.02, 0.01, single pulse D=0.5, 0.3, 0.1, 0.01, single pulse D=0.5, 0.3, 0.1, 0.05, 0.02, 0.01, single pulse D=0.5, 0.00, single pulse D=0.5, 0.00,

Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

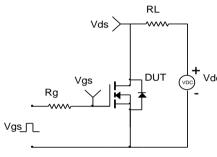


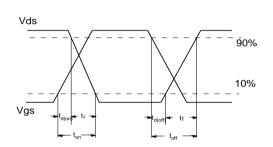
Gate Charge Test Circuit & Waveform



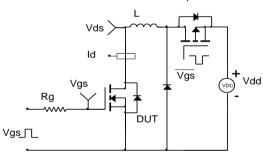


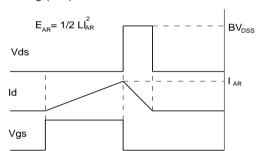
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

